

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination LUDWIG ET AL.	
		Examiner Monica M. Pyo	Art Unit 2161	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,174,339 B1	02-2007	Wucherer et al.	707/102
*	B	US-6,701,514 B1	03-2004	Haswell et al.	717/115
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mary Ann Robbert and Fred J. Maryanski; "Automated Test Plan Generator for Database Application Systems"; for Proceedings of the 1991 ACM SIGSMALL/PC symposium on Small systems, Toronto, Ontario, Canada; pages 100-106; Year Publication 1991.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.